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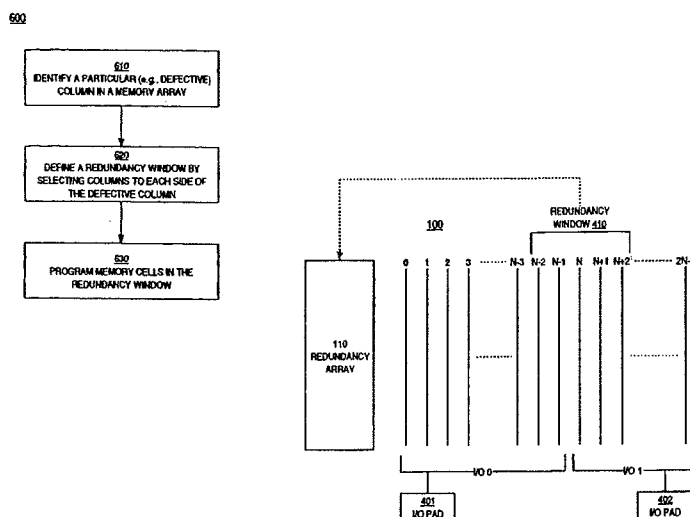
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(54) Title: **METHOD AND SYSTEM FOR DEFINING A REDUNDANCY WINDOW AROUND A PARTICULAR COLUMN IN A MEMORY ARRAY**



(57) Abstract: A method (600) of memory redundancy, and a system (100) thereof, are described. A memory array typically includes a plurality of columns (e.g., bit lines) of memory cells. A particular (e.g., defective) column of the memory array is identified (610). A redundancy window (410) is defined by selecting a group of adjacent columns including the defective column (620). The number of columns in the group of selected columns may be equal to the number of columns in a redundancy array (110) that is coupled to the memory array. The redundancy array is for storing information that would have been otherwise stored in the memory cells in the redundancy window. The group is selected such that there is at least one column on one side of the defective column and another column on the other side of the defective column. Typically, there will be multiple columns on each side of the defective column. The memory cells in these columns are programmed (630).



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